



Low switching losses
Low reverse recovery charge
Distributed amplified gate for high di_T/dt

Mean on-state current	I_{TAV}	700 A
Repetitive peak off-state voltage	V_{DRM}	3000 V
Repetitive peak reverse voltage	V_{RRM}	
Turn-off time	t_q	40.0; 50.0 μs
V_{DRM}, V_{RRM}, V		3000
Voltage code		30
$T_j, ^\circ C$		- 60 ÷ 120

MAXIMUM ALLOWABLE RATINGS

Symbols and parameters		Units	Values	Test conditions
ON-STATE				
I_{TAV}	Mean on-state current	A	700 1125	$T_c=87^\circ C$; Double side cooled; $T_c=55^\circ C$; Double side cooled; 180° half-sine wave; 50 Hz
I_{TRMS}	RMS on-state current	A	1100	$T_c=87^\circ C$; Double side cooled; 180° half-sine wave; 50 Hz
I_{TSM}	Surge on-state current	kA	14.0 16.0	180° half-sine wave; 50 Hz ($t_p=10$ ms); single pulse; $V_D=V_R=0$ V; Gate pulse: $I_G=I_{FGM}$; $V_G=20$ V; $t_{GP}=50$ μs ; $di_G/dt=1$ A/ μs
			15.0 17.0	180° half-sine wave; 60 Hz ($t_p=8.3$ ms); single pulse; $V_D=V_R=0$ V; Gate pulse: $I_G=I_{FGM}$; $V_G=20$ V; $t_{GP}=50$ μs ; $di_G/dt=1$ A/ μs
I^2t	Safety factor	$A^2s \cdot 10^3$	980 1280	180° half-sine wave; 50 Hz ($t_p=10$ ms); single pulse; $V_D=V_R=0$ V; Gate pulse: $I_G=I_{FGM}$; $V_G=20$ V; $t_{GP}=50$ μs ; $di_G/dt=1$ A/ μs
			930 1195	180° half-sine wave; 60 Hz ($t_p=8.3$ ms); single pulse; $V_D=V_R=0$ V; Gate pulse: $I_G=I_{FGM}$; $V_G=20$ V; $t_{GP}=50$ μs ; $di_G/dt=1$ A/ μs
BLOCKING				
V_{DRM}, V_{RRM}	Repetitive peak off-state and Repetitive peak reverse voltages	V	3000	$T_{j\ min} < T_j < T_{j\ max}$; 180° half-sine wave; 50 Hz; Gate open
V_{DSM}, V_{RSM}	Non-repetitive peak off-state and Non-repetitive peak reverse voltages	V	3100	$T_{j\ min} < T_j < T_{j\ max}$; 180° half-sine wave; 50 Hz; single pulse; Gate open
V_D, V_R	Direct off-state and Direct reverse voltages	V	0.75· V_{DRM} 0.75· V_{RRM}	$T_j=T_{j\ max}$; Gate open

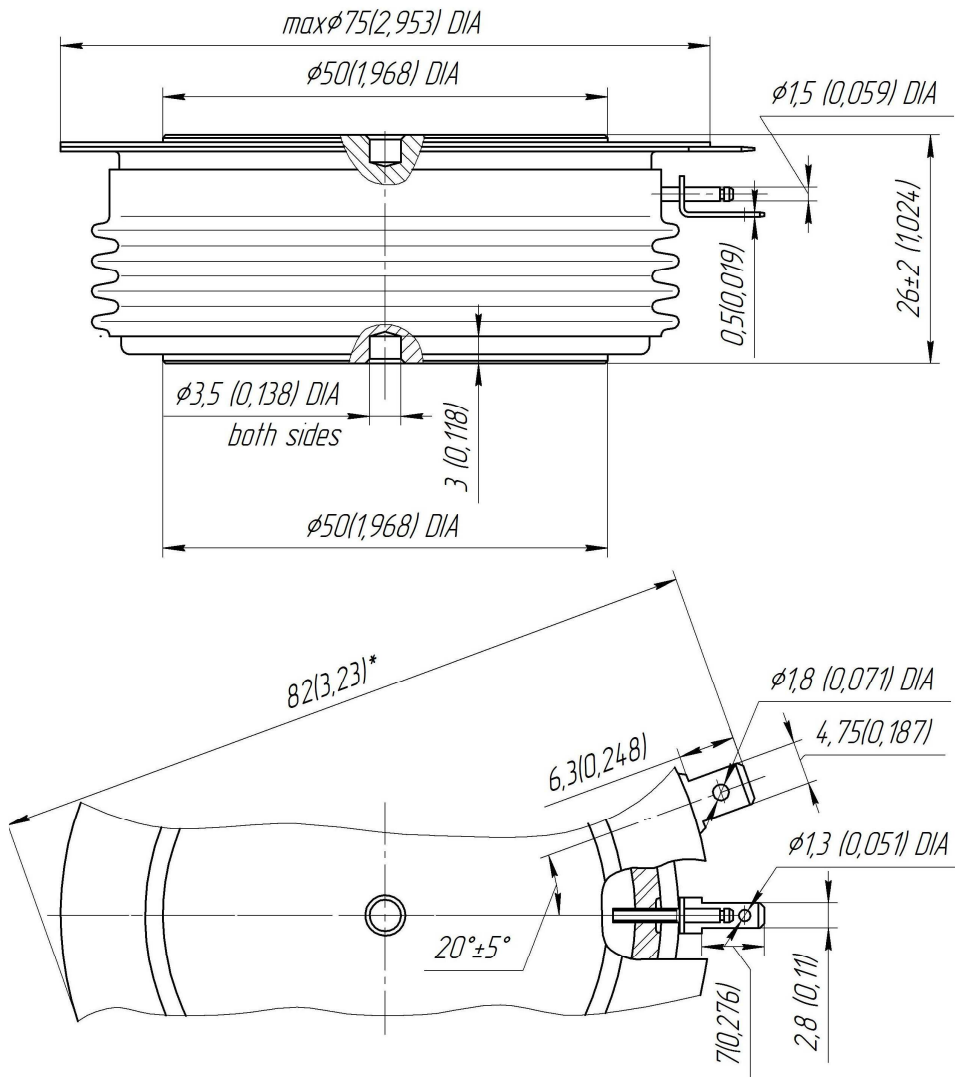
TRIGGERING				
I_{FGM}	Peak forward gate current	A	8	$T_j = T_{j\ max}$
V_{RGM}	Peak reverse gate voltage	V	5	
P_G	Gate power dissipation	W	8	$T_j = T_{j\ max}$ for DC gate current
SWITCHING				
$(di_T/dt)_{crit}$	Critical rate of rise of on-state current non-repetitive (f=1 Hz)	A/ μ s	2000	$T_j = T_{j\ max}; V_D = 0.67 \cdot V_{DRM}; I_{TM} = 2 I_{TAV};$ Gate pulse: $I_G = I_{FGM}; V_G = 20\ V;$ $t_{GP} = 50\ \mu s; di_G/dt = 1\ A/\mu s$
THERMAL				
T_{stg}	Storage temperature	$^{\circ}C$	-60 ÷ 120	
T_j	Operating junction temperature	$^{\circ}C$	-60 ÷ 120	
MECHANICAL				
F	Mounting force	kN	24.0 ÷ 28.0	
a	Acceleration	m/s^2	50 100	Device unclamped Device clamped

CHARACTERISTICS

Symbols and parameters		Units	Values	Conditions	
ON-STATE					
V_{TM}	Peak on-state voltage, max	V	3.20 2.85	$T_j = T_{j\ max}; I_{TM} = 3200\ A$ $T_j = 25\ ^{\circ}C; I_{TM} = 2512\ A$	
$V_{T(TO)}$	On-state threshold voltage, max	V	1.50	$T_j = T_{j\ max};$	
r_T	On-state slope resistance, max	$m\Omega$	0.500	$0.5 \pi I_{TAV} < I_T < 1.5 \pi I_{TAV}$	
I_H	Holding current, max	mA	500	$T_j = 25\ ^{\circ}C;$ $V_D = 12\ V;$ Gate open	
BLOCKING					
I_{DRM}, I_{RRM}	Repetitive peak off-state and Repetitive peak reverse currents, max	mA	150	$T_j = T_{j\ max};$ $V_D = V_{DRM}; V_R = V_{RRM}$	
$(dv_D/dt)_{crit}$	Critical rate of rise of off-state voltage ¹⁾ , min	V/ μ s	1000	$T_j = T_{j\ max};$ $V_D = 0.67 \cdot V_{DRM};$ Gate open	
TRIGGERING					
V_{GT}	Gate trigger direct voltage, max	V	4.00 2.50 2.00	$T_j = T_{j\ min}$ $T_j = 25\ ^{\circ}C$ $T_j = T_{j\ max}$	$V_D = 12\ V; I_D = 3\ A;$ Direct gate current
I_{GT}	Gate trigger direct current, max	mA	500 300 200	$T_j = T_{j\ min}$ $T_j = 25\ ^{\circ}C$ $T_j = T_{j\ max}$	
V_{GD}	Gate non-trigger direct voltage, min	V	0.25	$T_j = T_{j\ max}; V_D = 0.67 \cdot V_{DRM};$	
I_{GD}	Gate non-trigger direct current, min	mA	10.00	Direct gate current	
SWITCHING					
t_{gd}	Delay time	μ s	3.00	$T_j = 25\ ^{\circ}C; V_D = 0.4 \cdot V_{DRM}; I_{TM} = I_{TAV};$ Gate pulse: $I_G = I_{FGM}; V_G = 20\ V;$ $t_{GP} = 50\ \mu s; di_G/dt = 1\ A/\mu s$	
t_q	Turn-off time ²⁾ , max	μ s	40.0; 50.0	$dv_D/dt = 50\ V/\mu s;$	$T_j = T_{j\ max};$ $I_{TM} = I_{TAV};$ $di_R/dt = -10\ A/\mu s;$ $V_R = 100V;$ $V_D = 0.67\ V_{DRM}$
			50.0; 63.0	$dv_D/dt = 200\ V/\mu s;$	
Q_{rr}	Total recovered charge, max	μ C	770	$T_j = T_{j\ max}; I_{TM} = I_{TAV};$	
t_{rr}	Reverse recovery time, typ	μ s	7.0	$di_R/dt = -50\ A/\mu s;$	
I_{rrM}	Peak reverse recovery current, max	A	220	$V_R = 100\ V$	

THERMAL					
R_{thjc}	Thermal resistance, junction to case, max	°C/W	0.0200	Direct current	Double side cooled
R_{thjc-A}			0.0440		Anode side cooled
R_{thjc-K}			0.0360		Cathode side cooled
R_{thck}	Thermal resistance, case to heatsink, max	°C/W	0.0040	Direct current	
MECHANICAL					
w	Weight, typ	g	510		
D_s	Surface creepage distance	mm (inch)	30.38 (1.196)		
D_a	Air strike distance	mm (inch)	18.05 (0.710)		

NOTES			PART NUMBERING GUIDE																												
¹⁾ Critical rate of rise of off-state voltage <table border="1"> <tr> <td>Symbol of group</td> <td colspan="2">A2</td> </tr> <tr> <td>$(dv_D/dt)_{crit}$, V/μs</td> <td colspan="2">1000</td> </tr> </table>			Symbol of group	A2		$(dv_D/dt)_{crit}$, V/ μ s	1000		<table border="1"> <tr> <td>TFI</td> <td>353</td> <td>700</td> <td>30</td> <td>A2</td> <td>H3</td> <td colspan="2">N</td> </tr> <tr> <td>1</td> <td>2</td> <td>3</td> <td>4</td> <td>5</td> <td>6</td> <td colspan="2">7</td> </tr> </table>							TFI	353	700	30	A2	H3	N		1	2	3	4	5	6	7	
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²⁾ Turn-off time ($dv_D/dt=50$ V/ μ s) <table border="1"> <tr> <td>Symbol of group</td> <td>H3</td> <td>E3</td> </tr> <tr> <td>t_{qT}, μs</td> <td>40.0</td> <td>50.0</td> </tr> </table>			Symbol of group	H3	E3	t_{qT} , μ s	40.0	50.0	<ol style="list-style-type: none"> TFI — Fast Thyristor TFIS — Fast Thyristor with Distributed Amplified Gate Design version Mean on-state current, A Voltage code Critical rate of rise of off-state voltage Group of turn-off time ($dv_D/dt=50$ V/μs) Ambient conditions: N – normal; T – tropical 																						
Symbol of group	H3	E3																													
t_{qT} , μ s	40.0	50.0																													



All dimensions in millimeters (inches)

On-state characteristic model (see Fig. 1).

Analytical function for On-state characteristic:

$$V_T = A + B \cdot i_T + C \cdot \ln(i_T + 1) + D \cdot \sqrt{i_T}$$

	Coefficients	
	T _j = 25°C	T _j = T _{j max}
A	1.967194	1.329742
B	0.254400	0.439131
C	-0.166422	-0.222268
D	0.285964	0.381925

Transient thermal impedance junction to case Z_{thjc} model (see Fig. 2).

Analytical function for Transient thermal impedance junction to case Z_{thjc} for DC:

$$Z_{thjc} = \sum_{i=1}^n R_i \left(1 - e^{-\frac{t}{\tau_i}} \right)$$

Where *i* = 1 to *n*, *n* is the number of terms in the series.

t = Duration of heating pulse in seconds.

Z_{thjc} = Thermal resistance at time *t*.

R_i = Amplitude of p_{th} term.

τ_i = Time constant of r_{th} term.

DC Double side cooled

i	1	2	3	4	5	6
R_i K/W	-1.888e-006	0.009096	0.009331	0.0001969	0.001089	0.000289
τ_i s	9.752	0.9752	0.06926	0.02587	0.00197	0.0004773

DC Anode side cooled

i	1	2	3	4	5	6
R_i K/W	0.02418	0.009264	0.00939	3.212e-007	0.001074	0.0003088
τ_i s	9.752	1.078	0.07024	0.2399	0.00201	0.0005003

DC Cathode side cooled

i	1	2	3	4	5	6
R_i K/W	0.01613	0.008994	0.00918	0.0004987	0.001111	0.0002592
τ_i s	9.752	1.077	0.06877	0.2401	0.001906	0.0004449

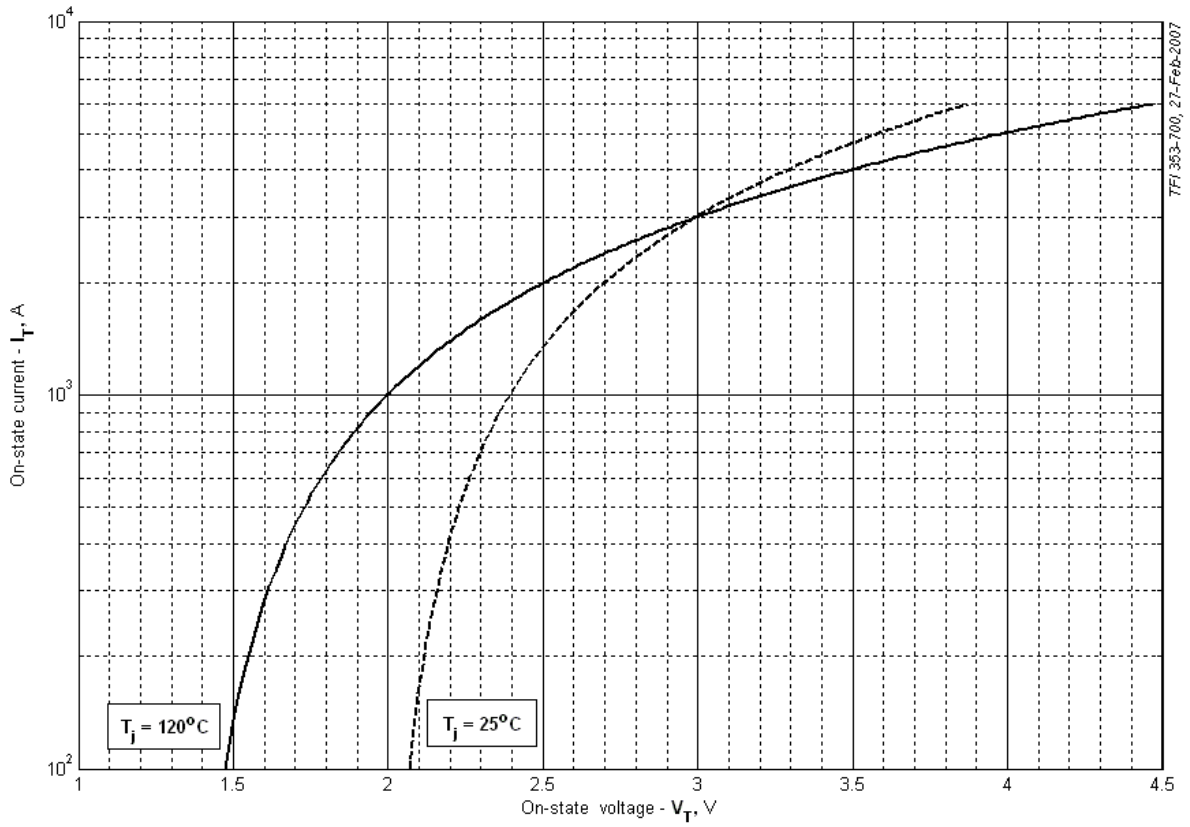


Fig 1 – On-state characteristics of Limit device

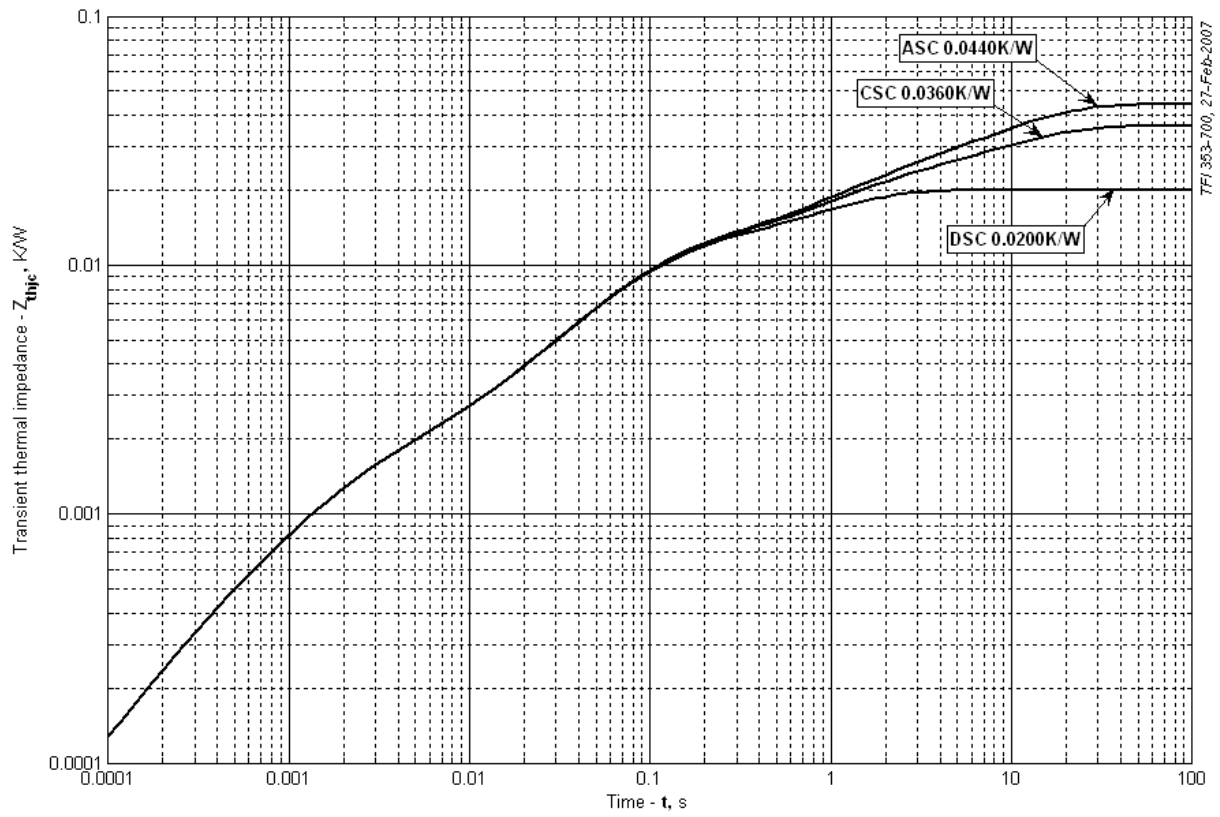


Fig 2 – Transient thermal impedance

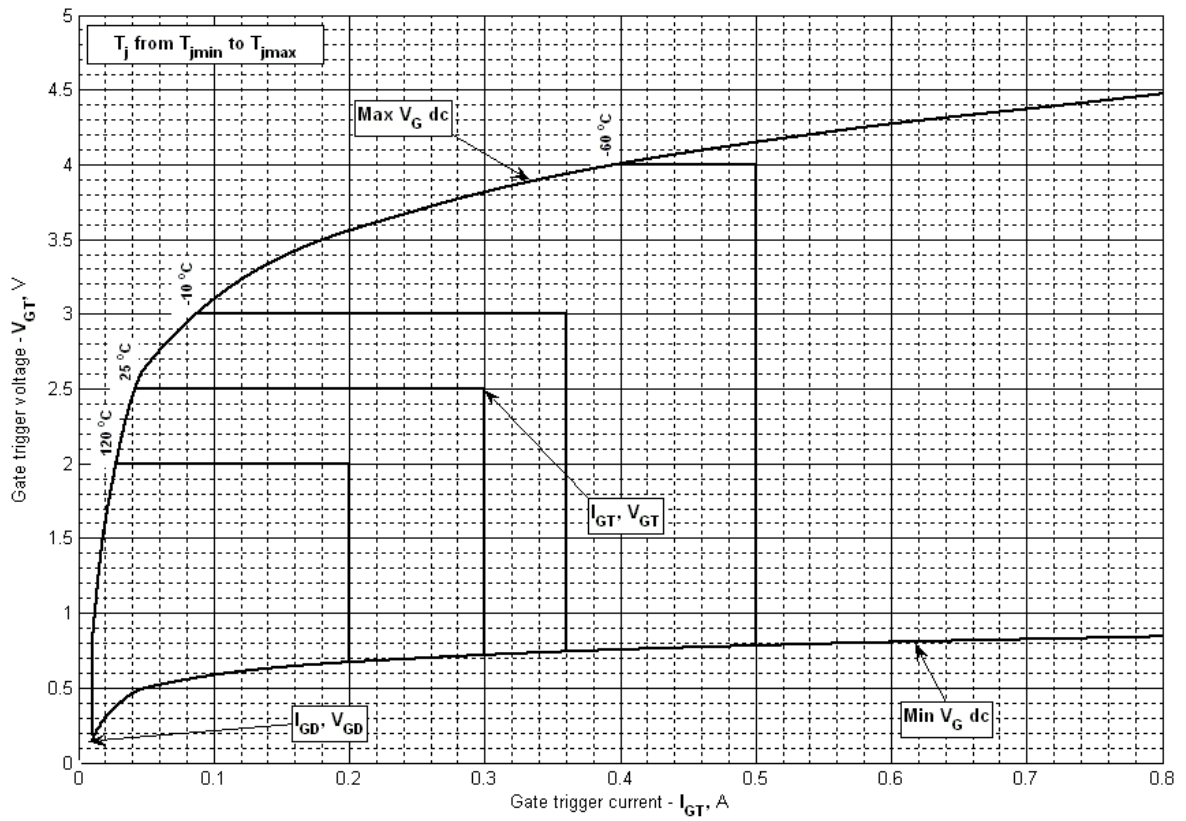


Fig 3 – Gate characteristics – Trigger limits

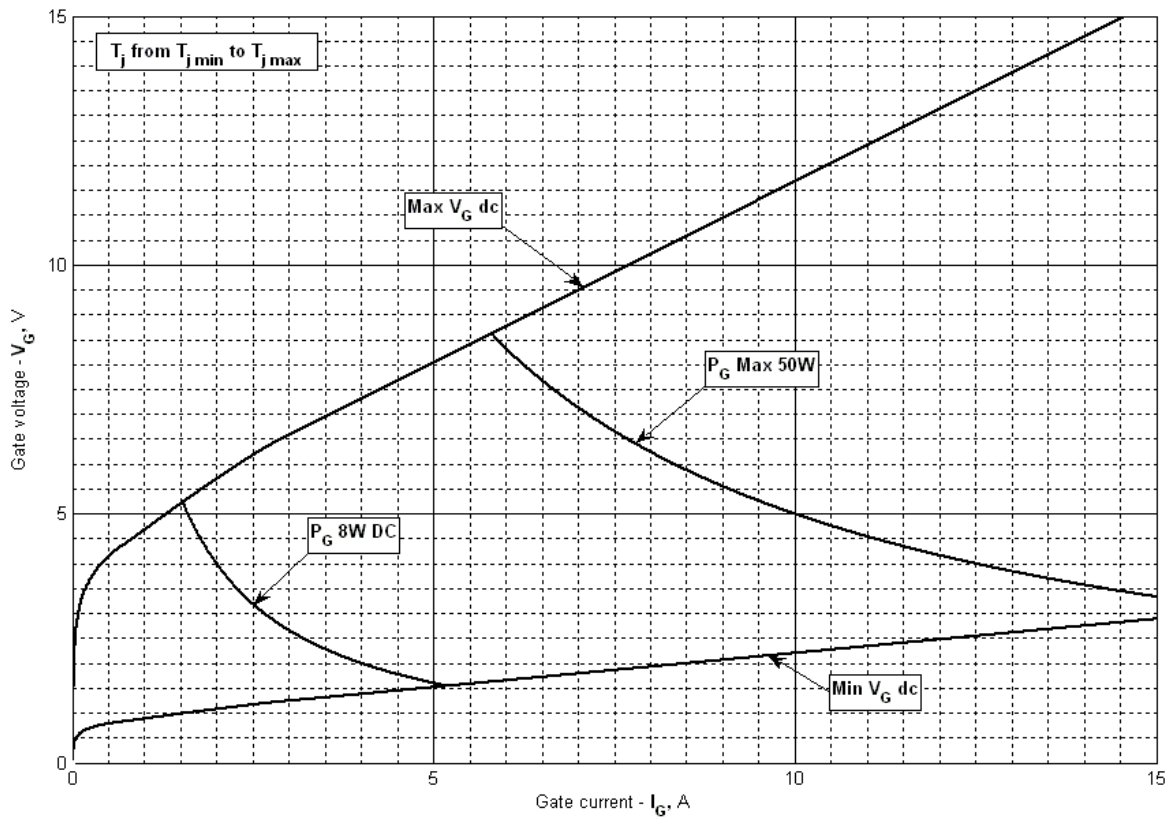


Fig 4 - Gate characteristics –Power curves

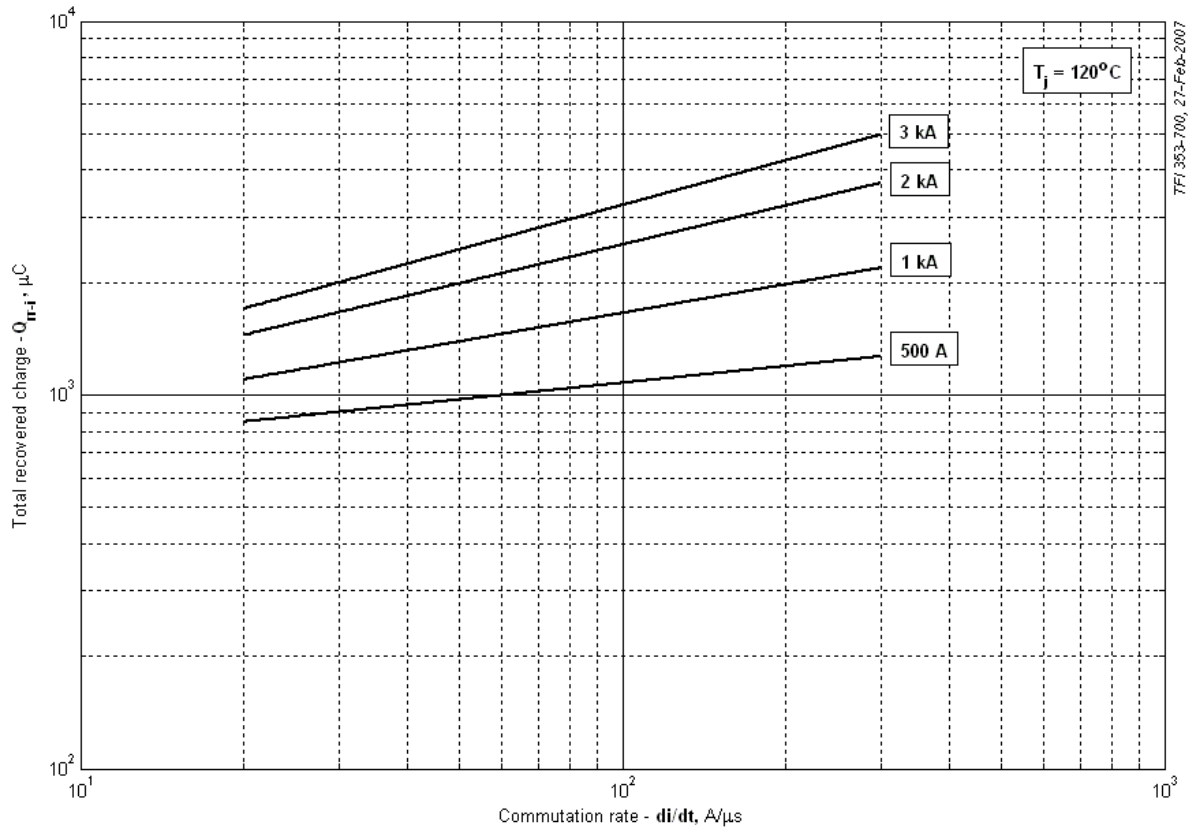


Fig 5 – Total recovered charge, Q_{rr-i} (integral)

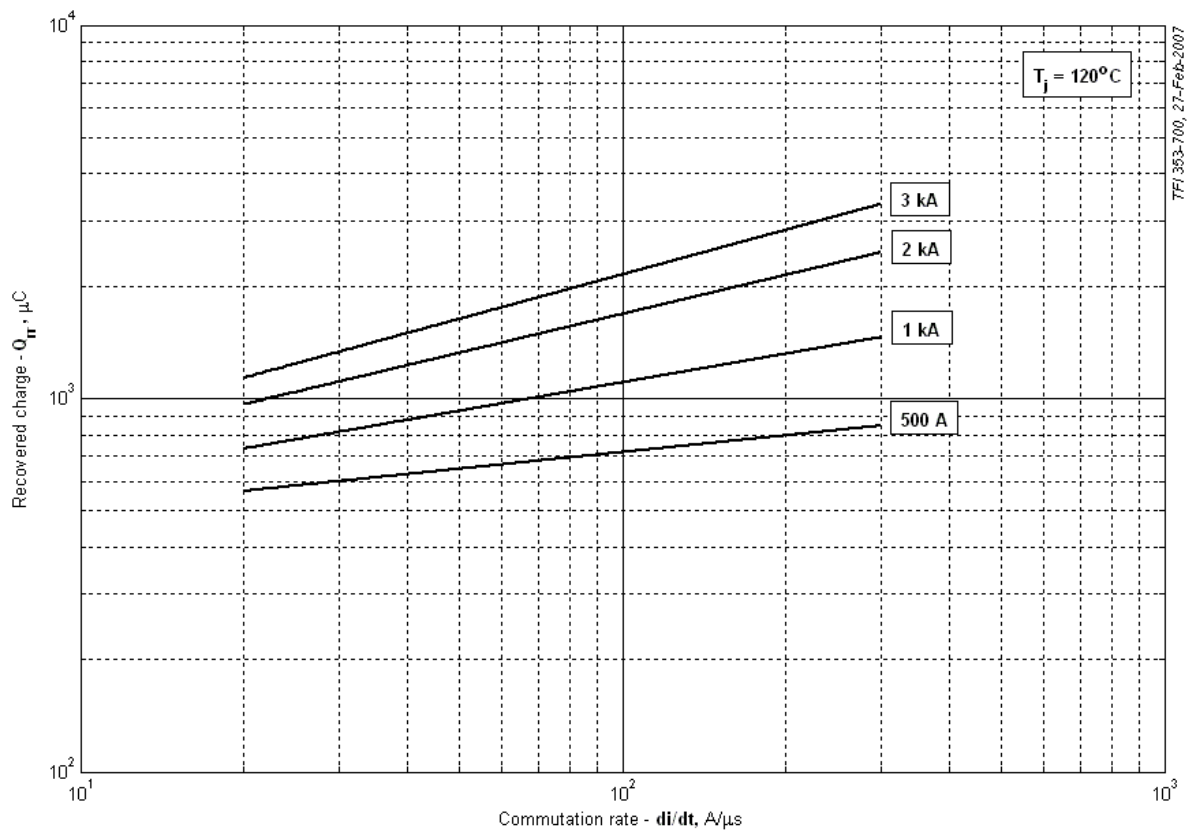


Fig 6 - Recovered charge, Q_{rr} (linear)

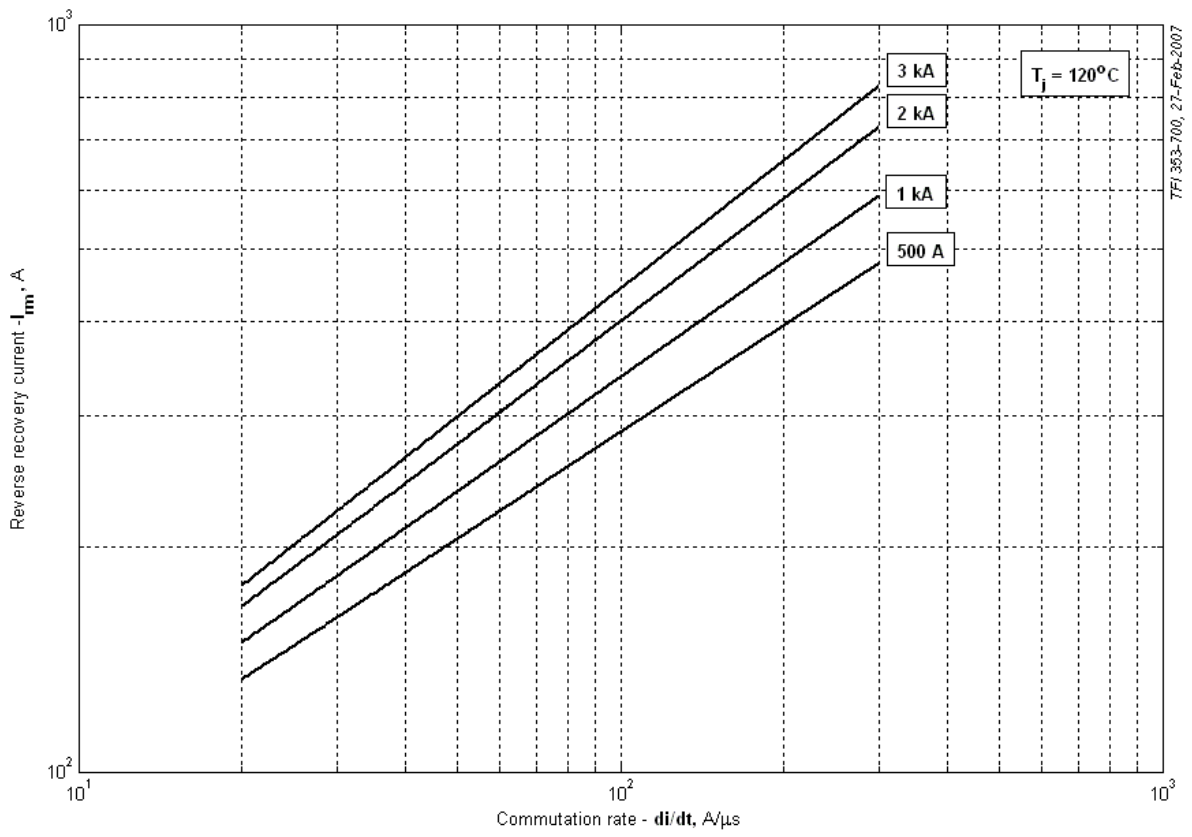


Fig 7 – Peak reverse recovery current, I_{fm}

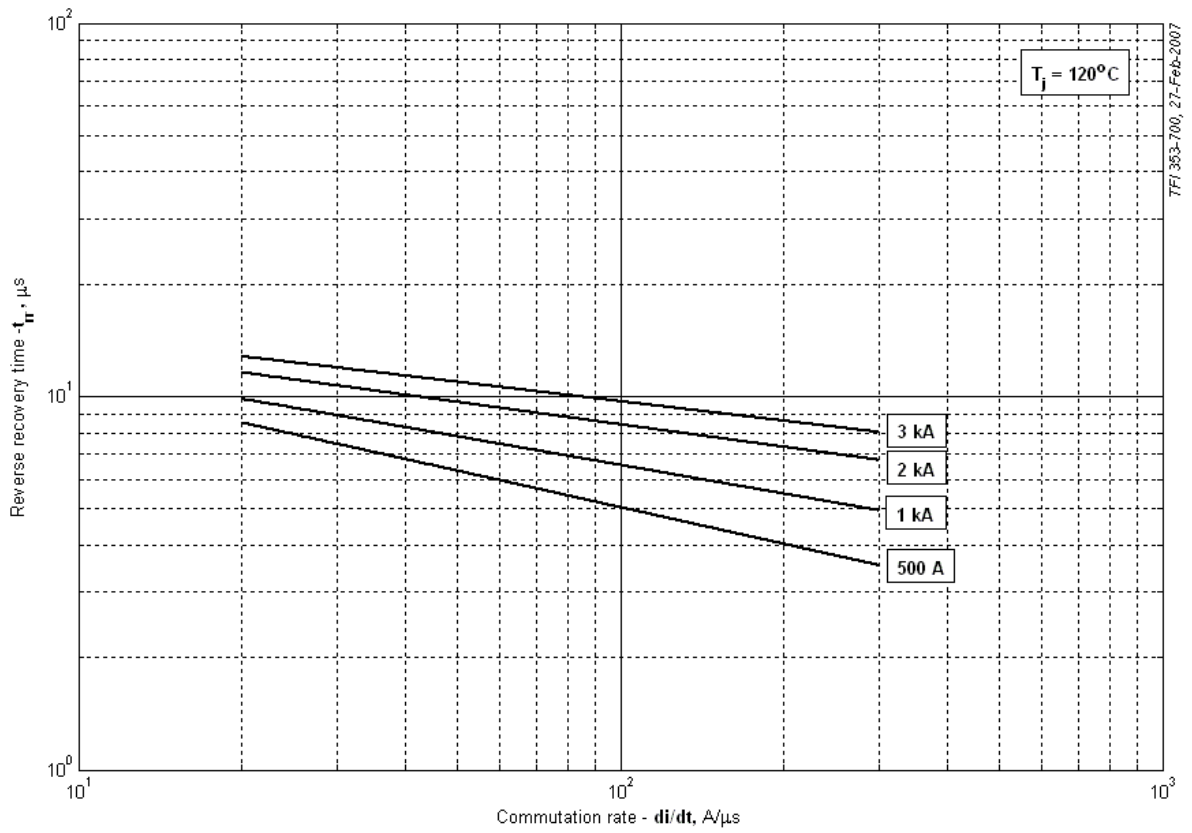


Fig 8 – Maximum recovery time, t_{tr} (linear)

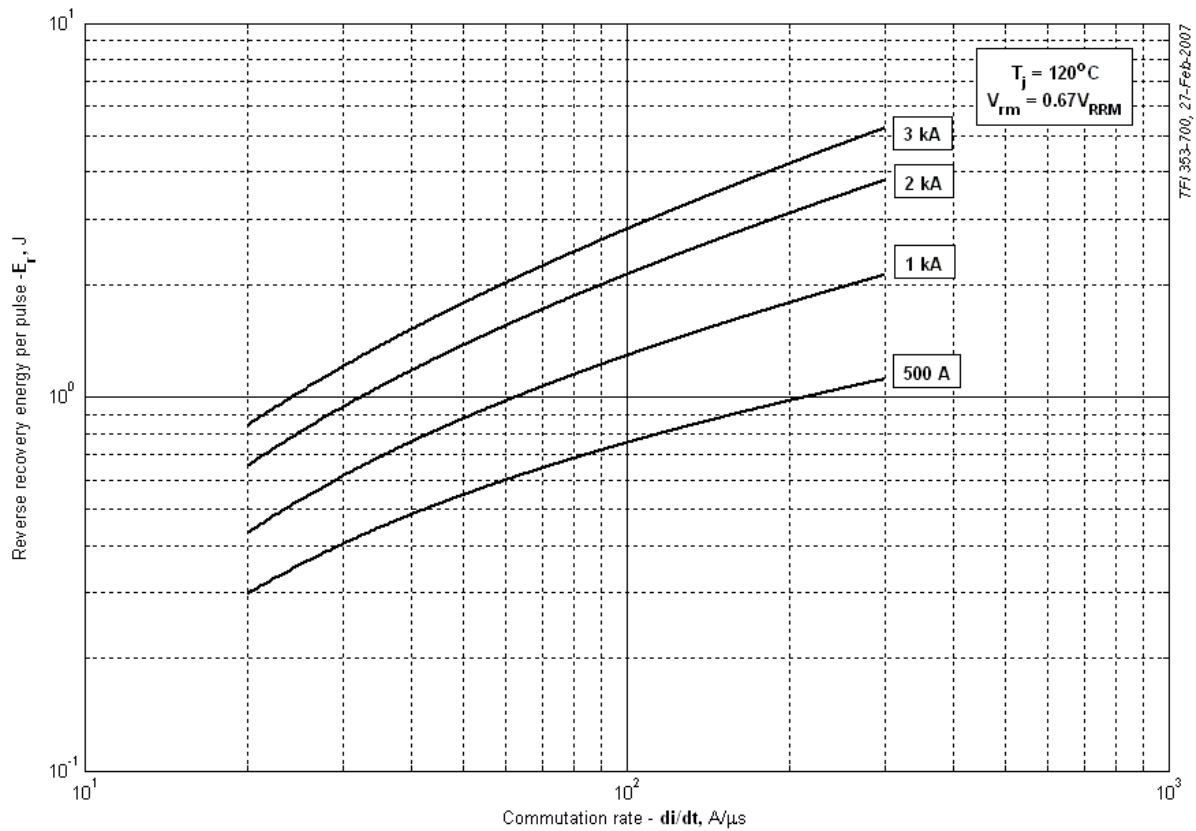


Fig 9 – Reverse recovery energy per pulse

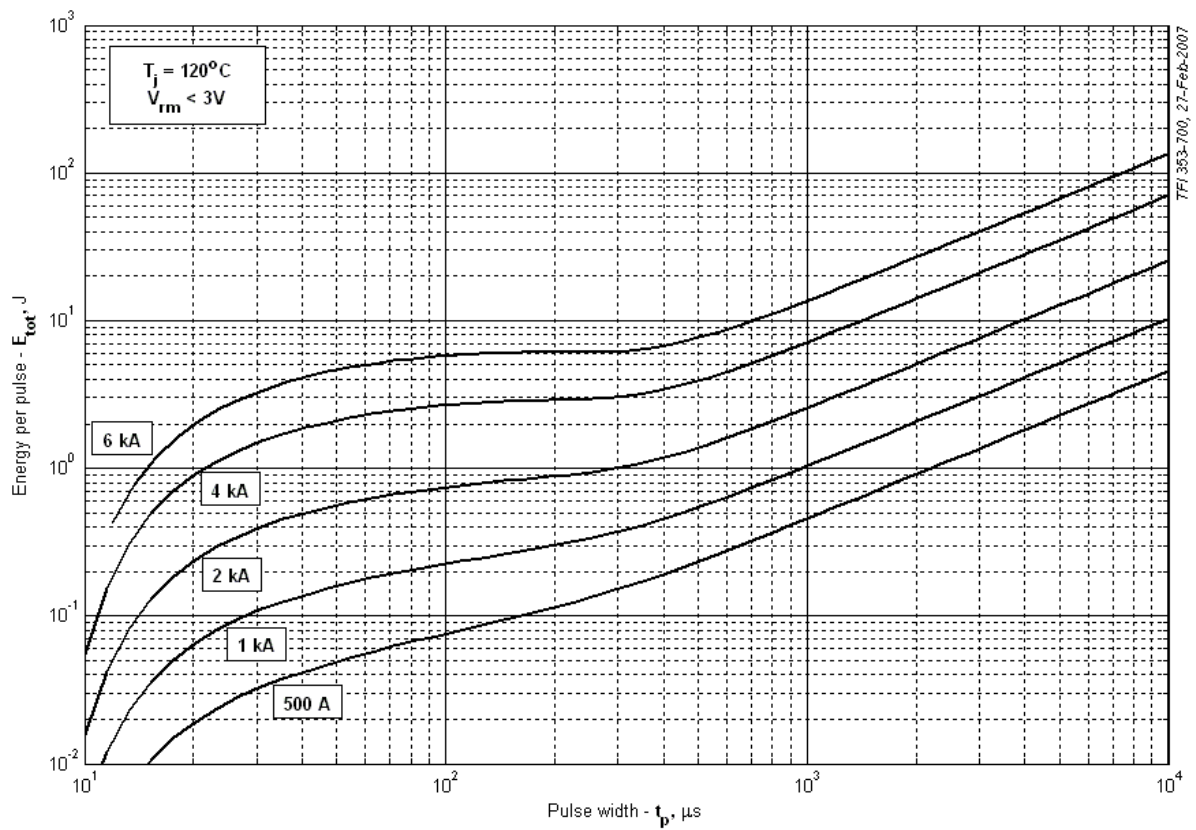


Fig 10 – Sine wave energy per pulse

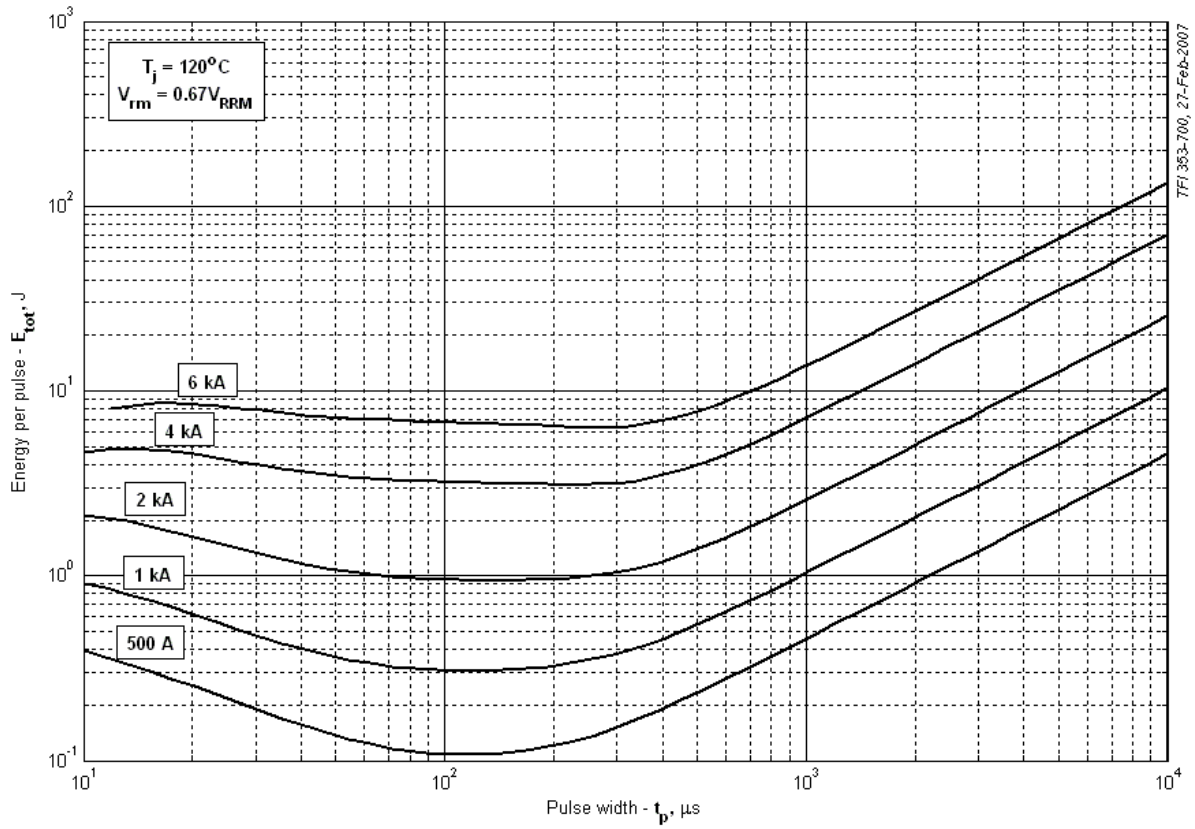


Fig 11 – Sine wave energy per pulse

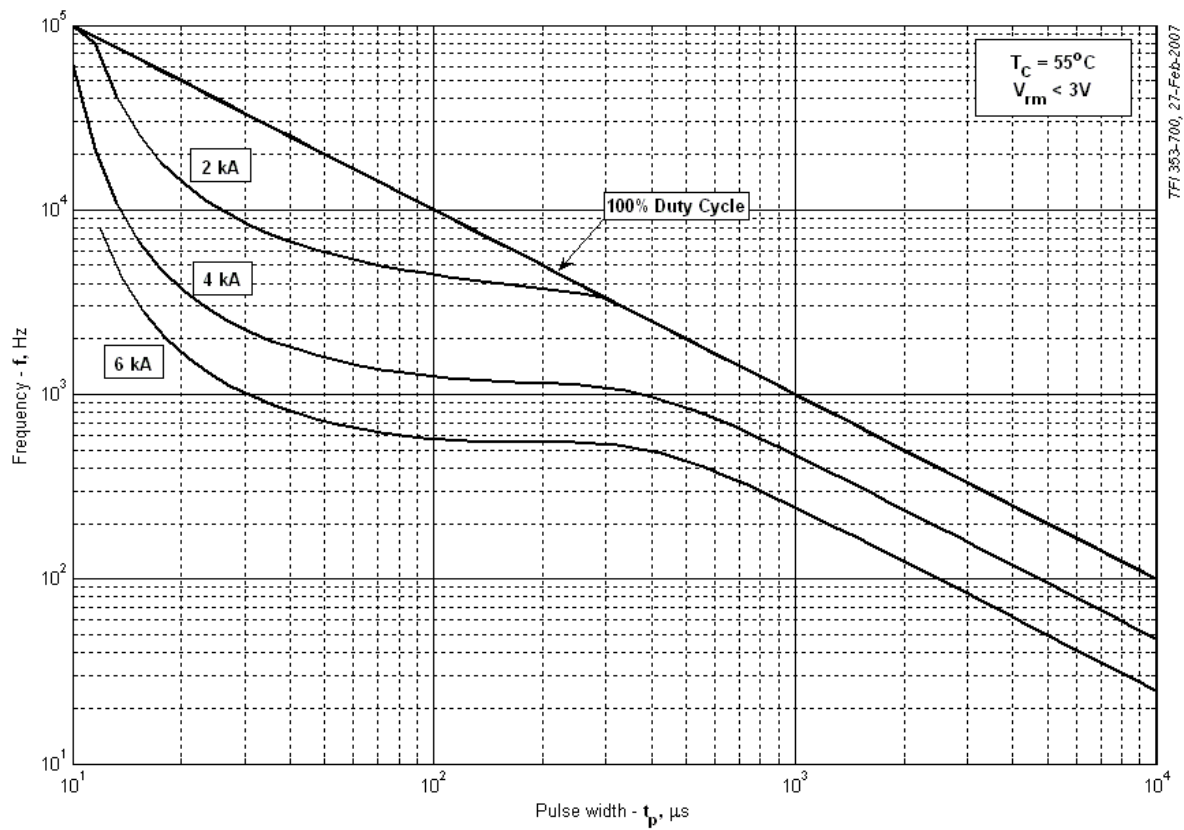
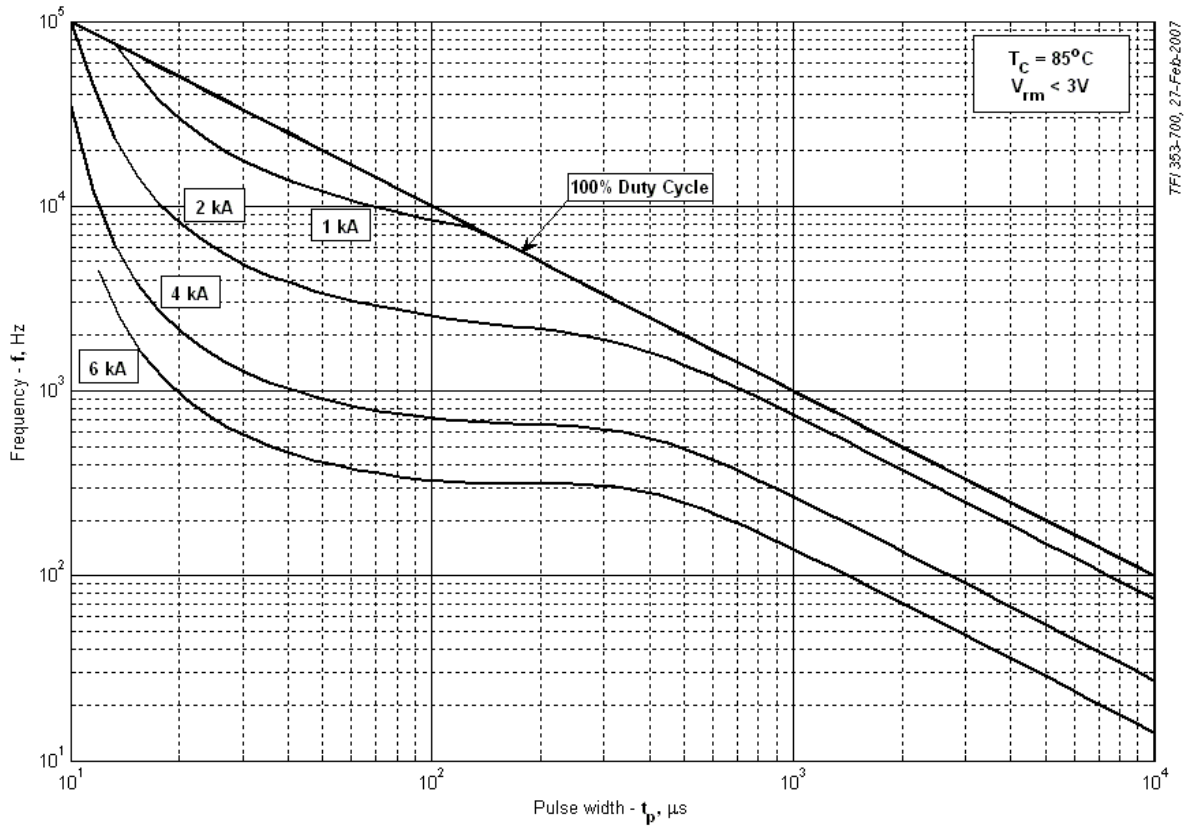
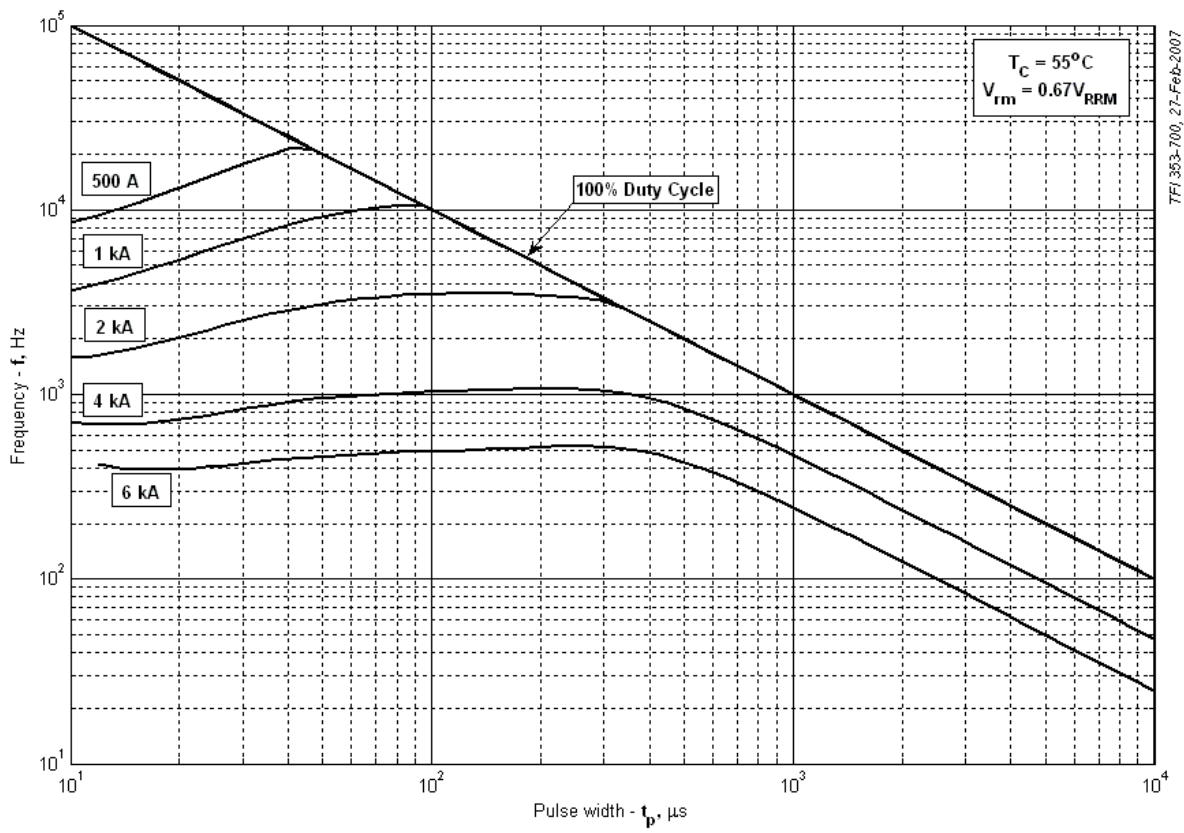


Fig 12 – Sine wave frequency ratings



TFI 353-700, 27-Feb-2007

Fig 13 – Sine wave frequency ratings



TFI 353-700, 27-Feb-2007

Fig 14 – Sine wave frequency ratings

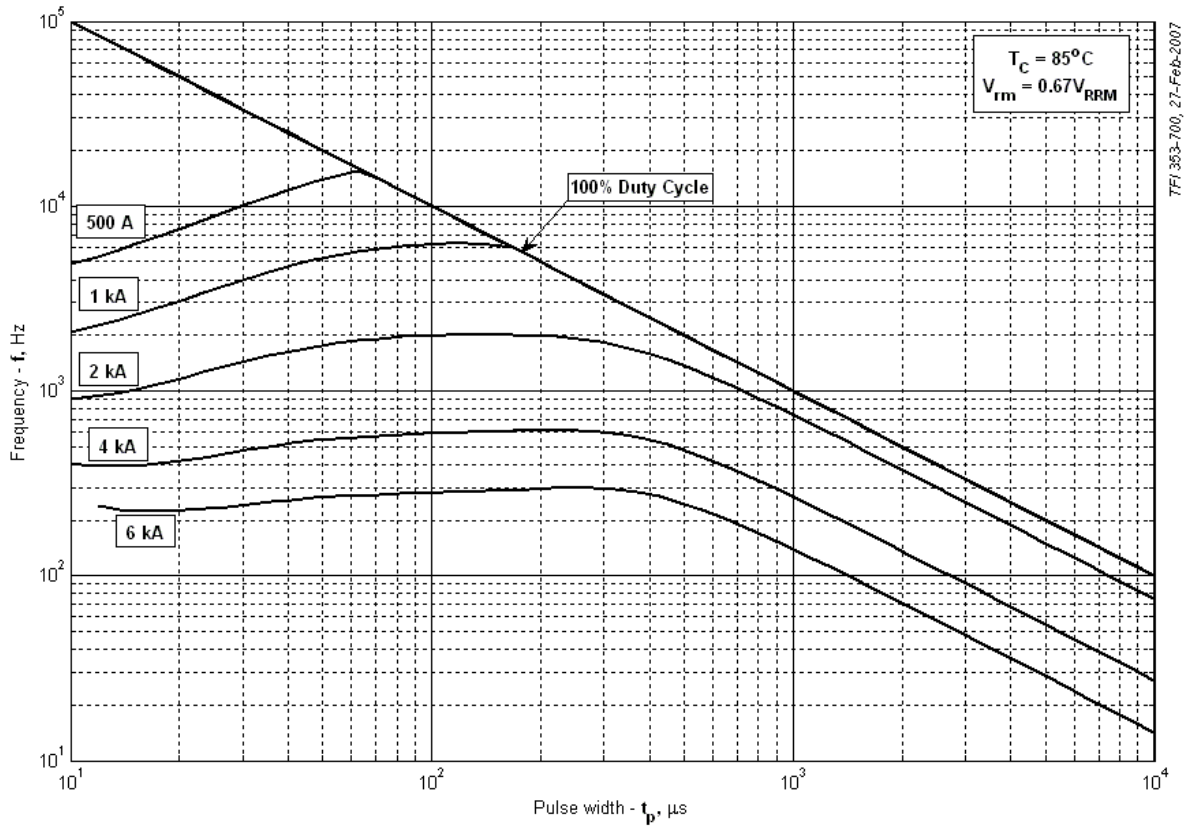


Fig 15 – Sine wave frequency ratings

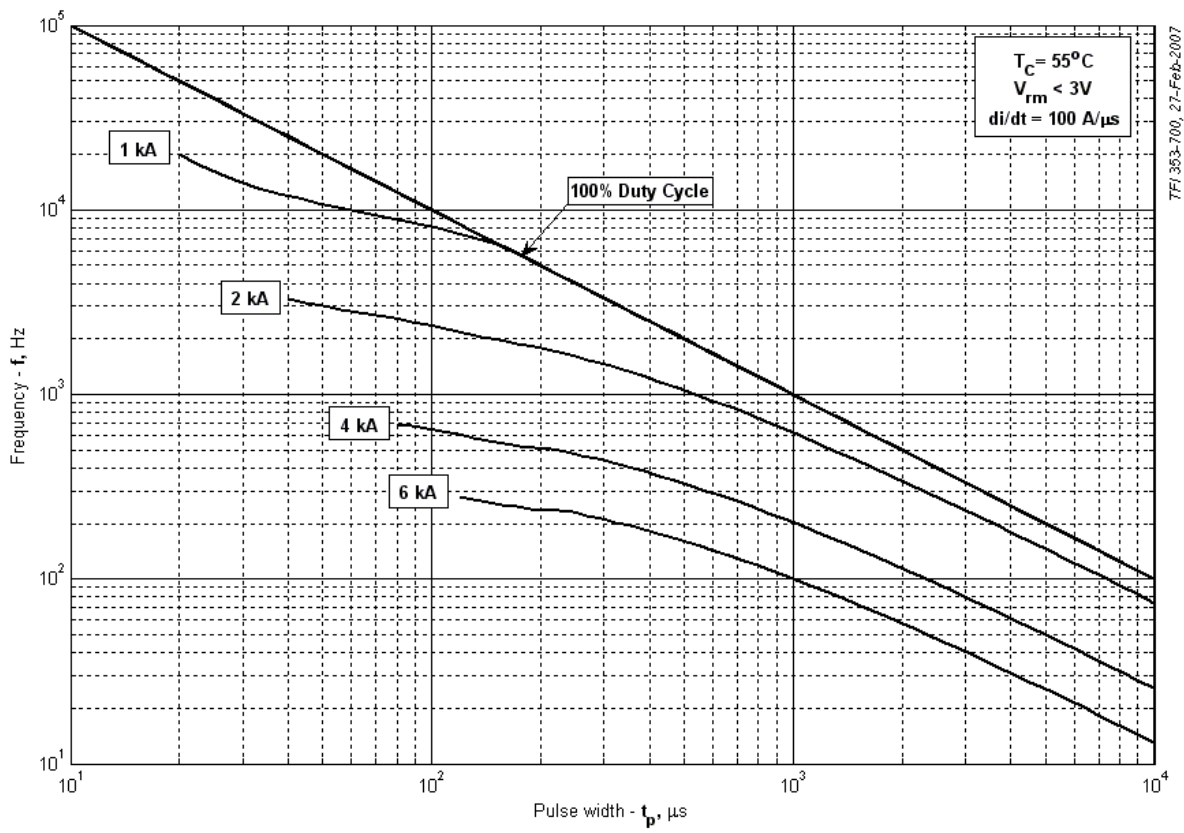


Fig 16 – Square wave frequency ratings

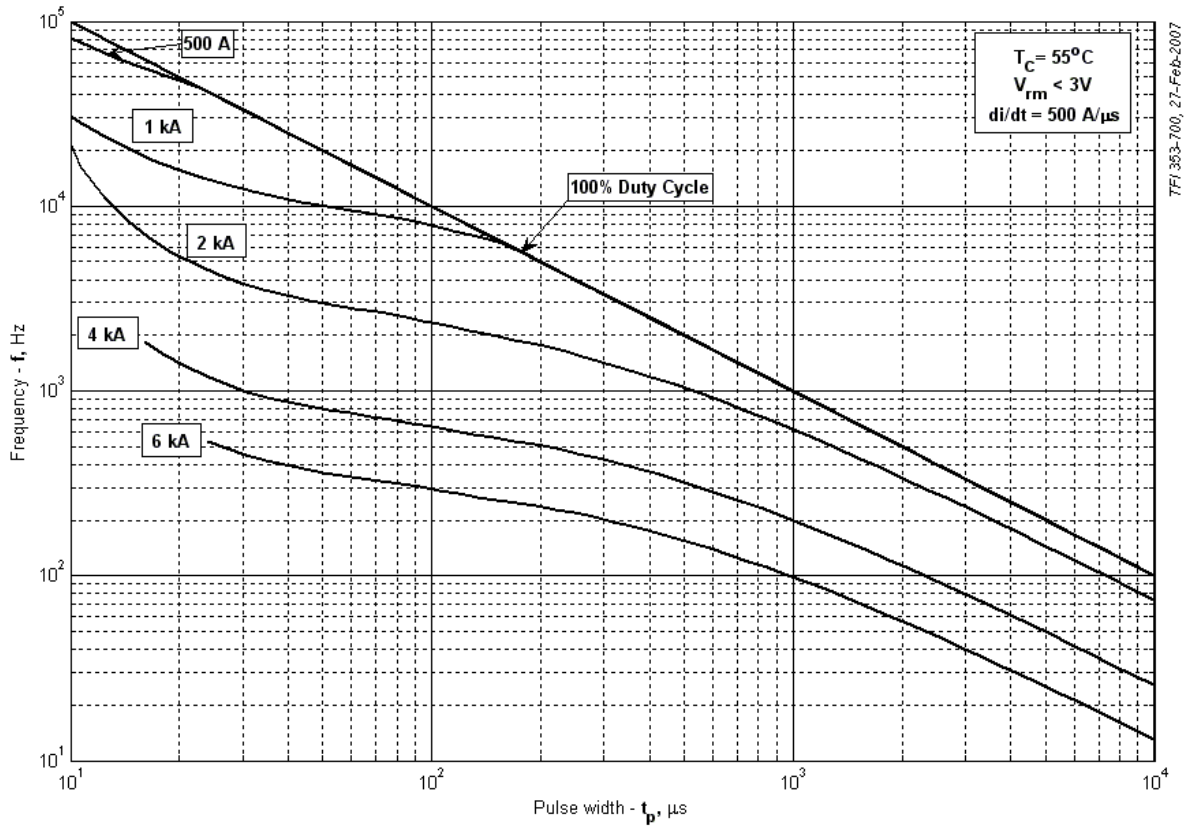


Fig 17 – Square wave frequency ratings

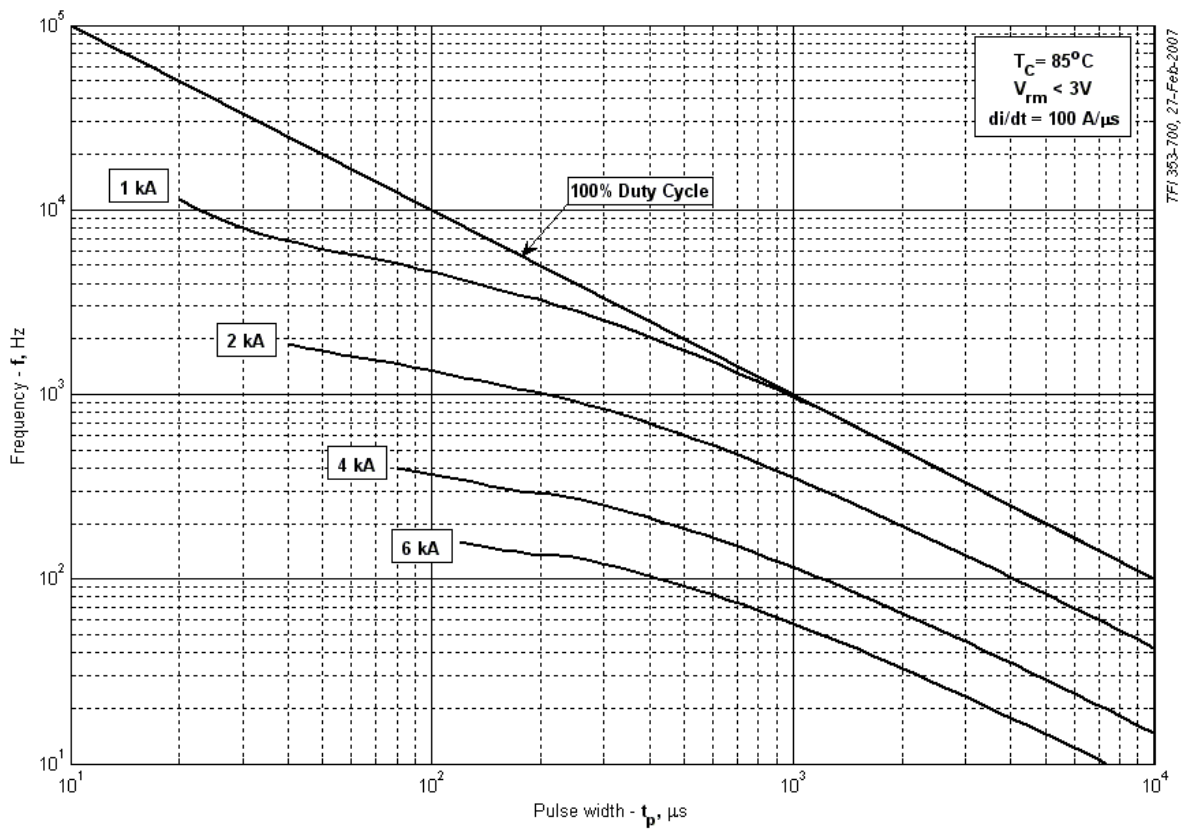


Fig 18 – Square wave frequency ratings

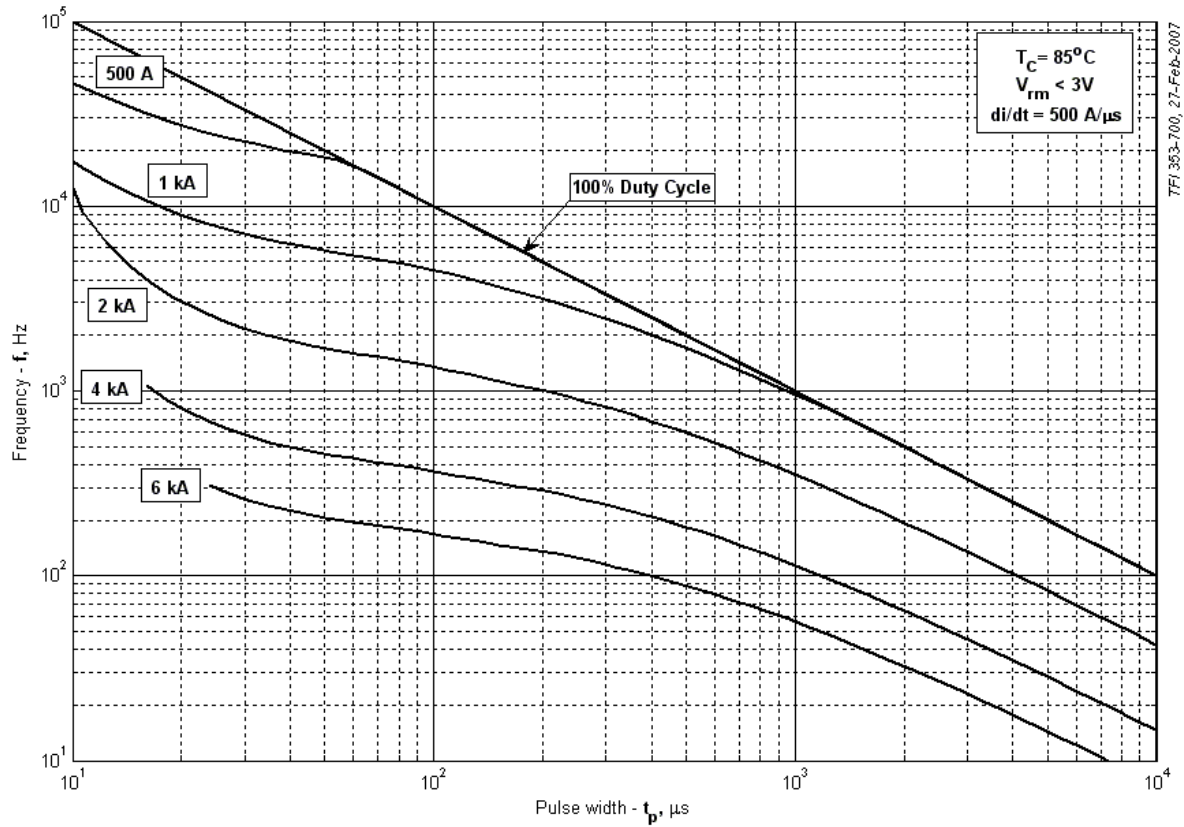


Fig 19 – Square wave frequency ratings

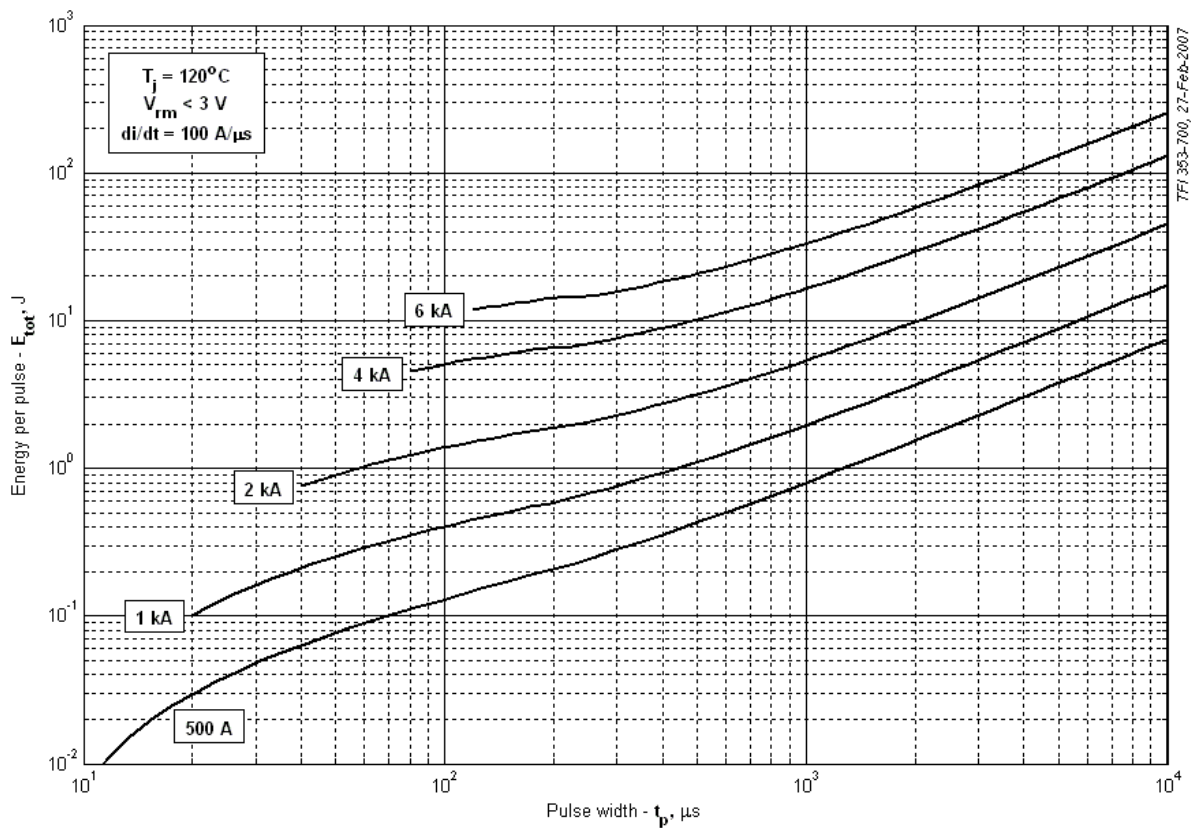


Fig 20 – Square wave energy per pulse

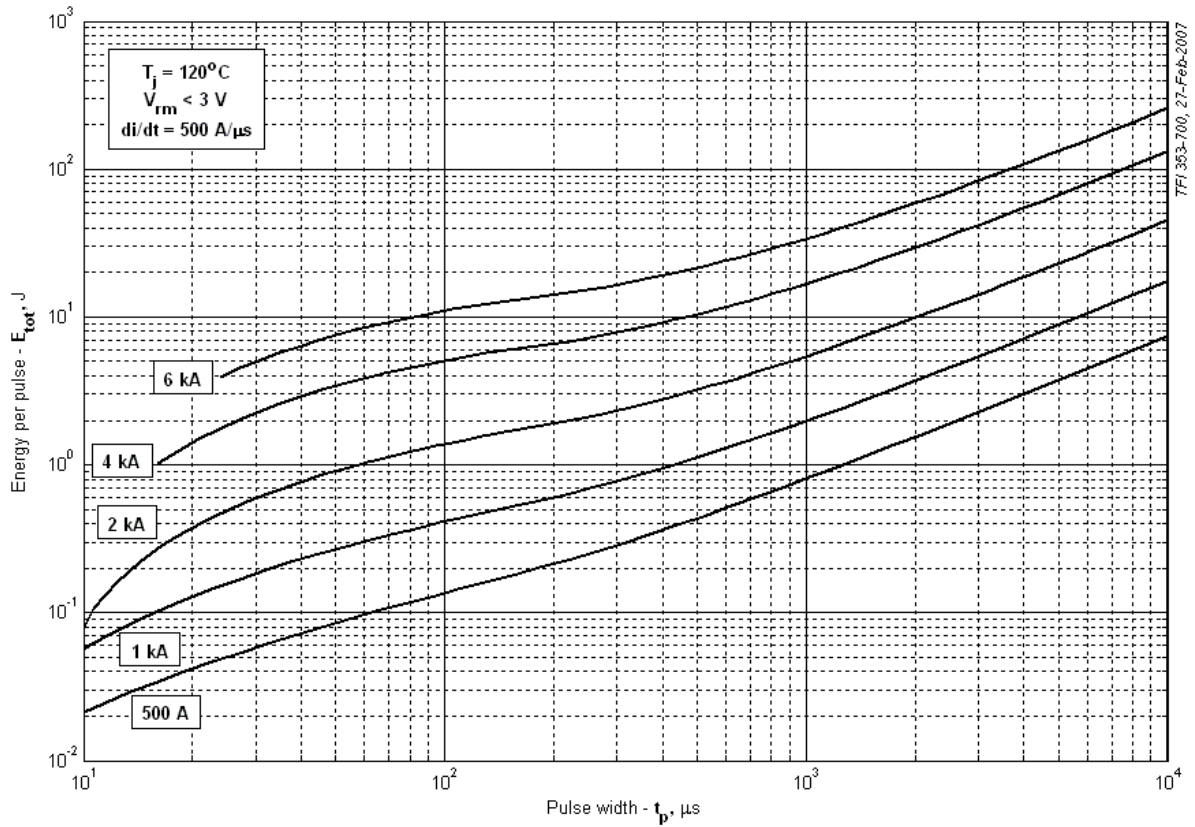


Fig 21 – Square wave energy per pulse

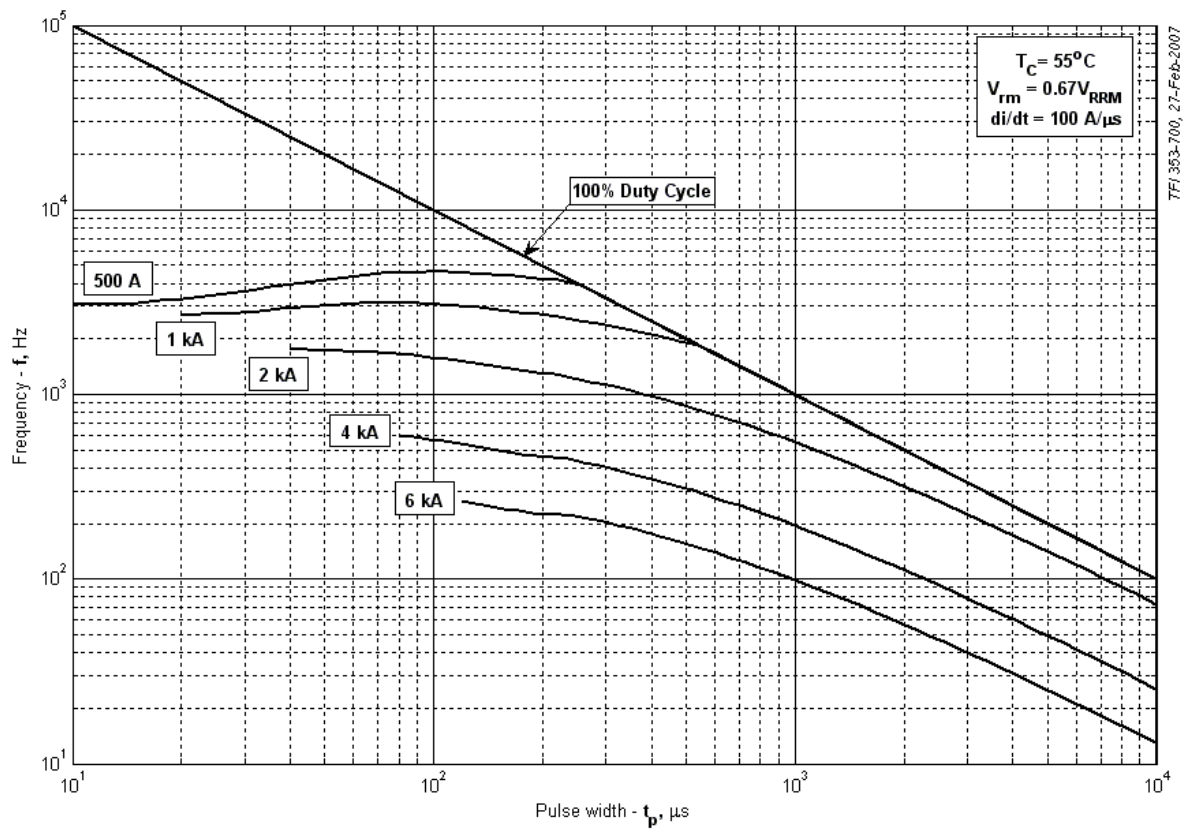


Fig 22 – Square wave frequency ratings

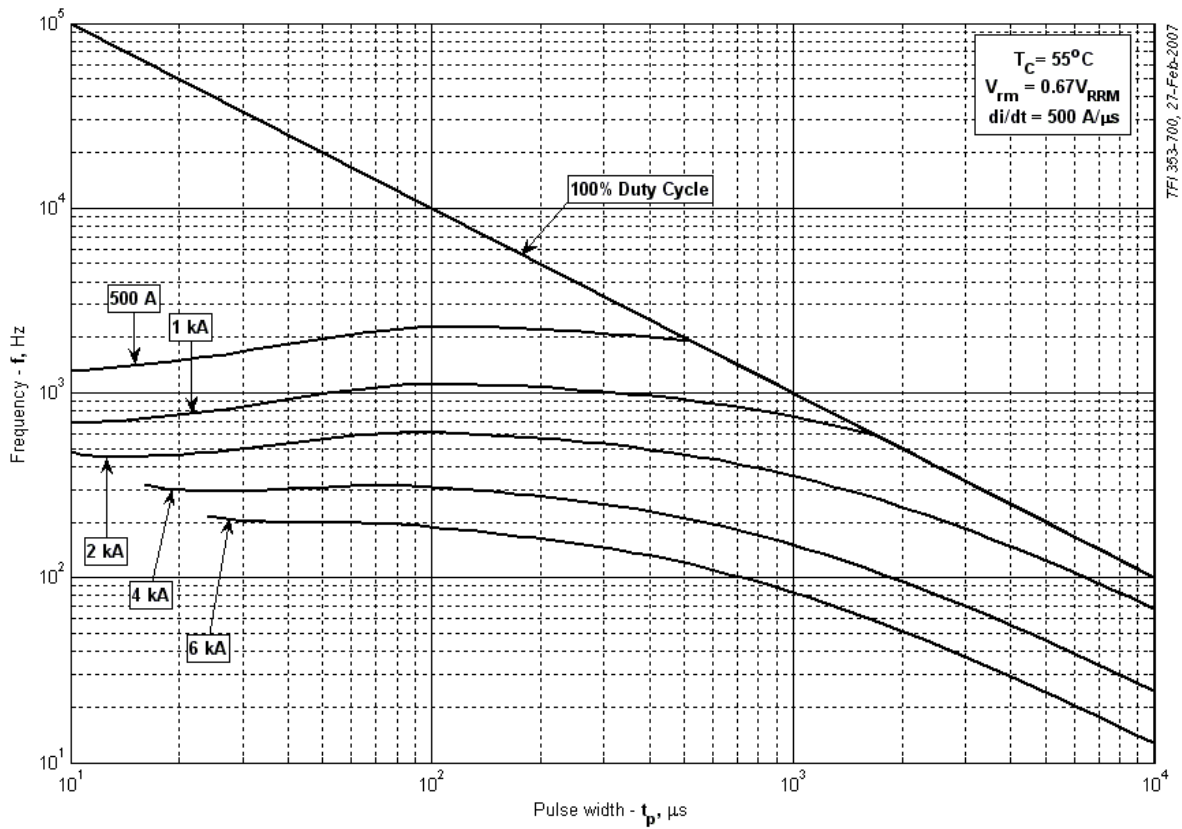


Fig 23 – Square wave frequency ratings

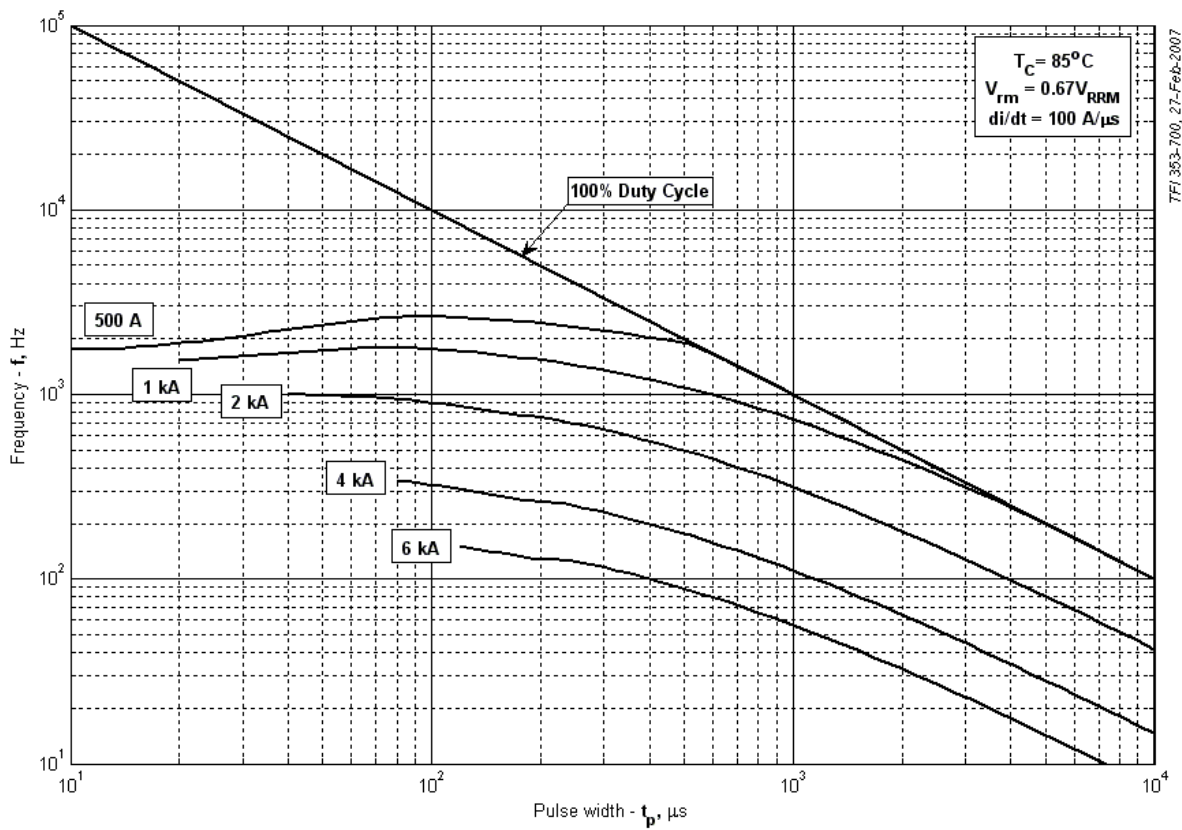


Fig 24 – Square wave frequency ratings

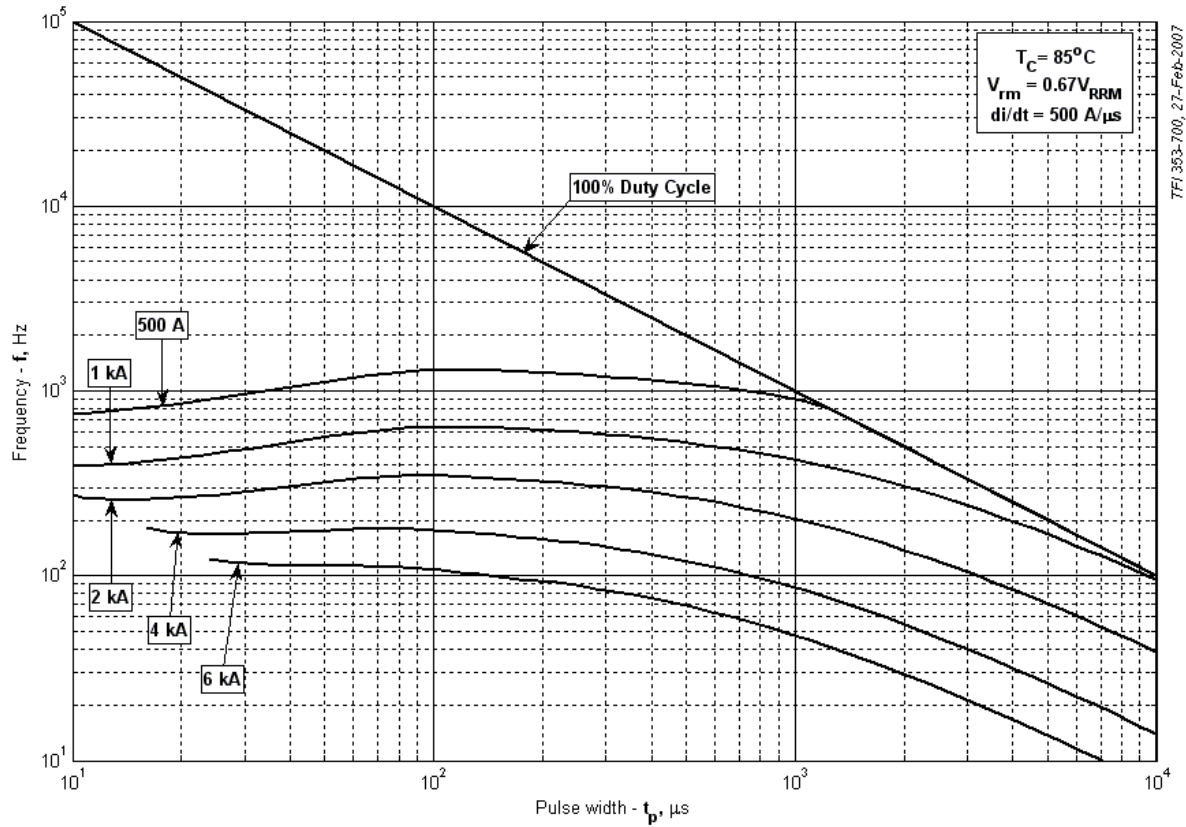


Fig 25 – Square wave frequency ratings

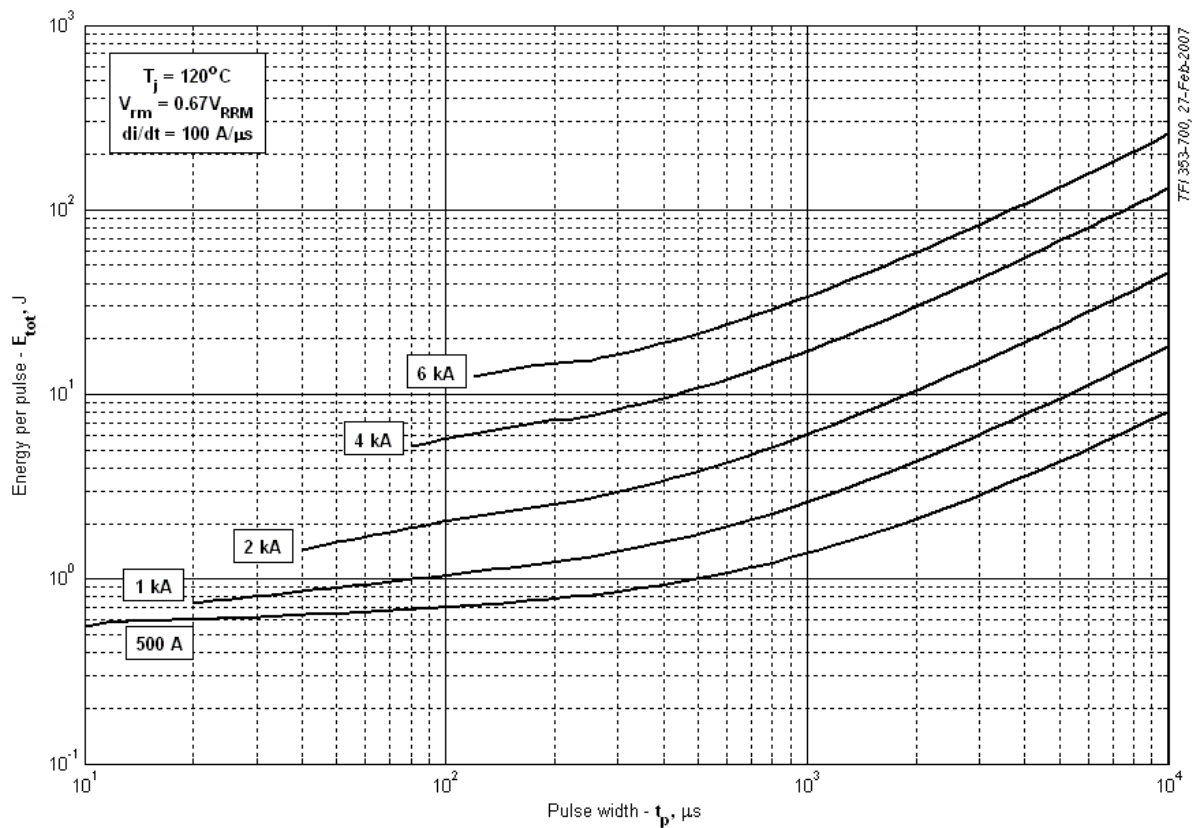


Fig 26 – Square wave energy per pulse

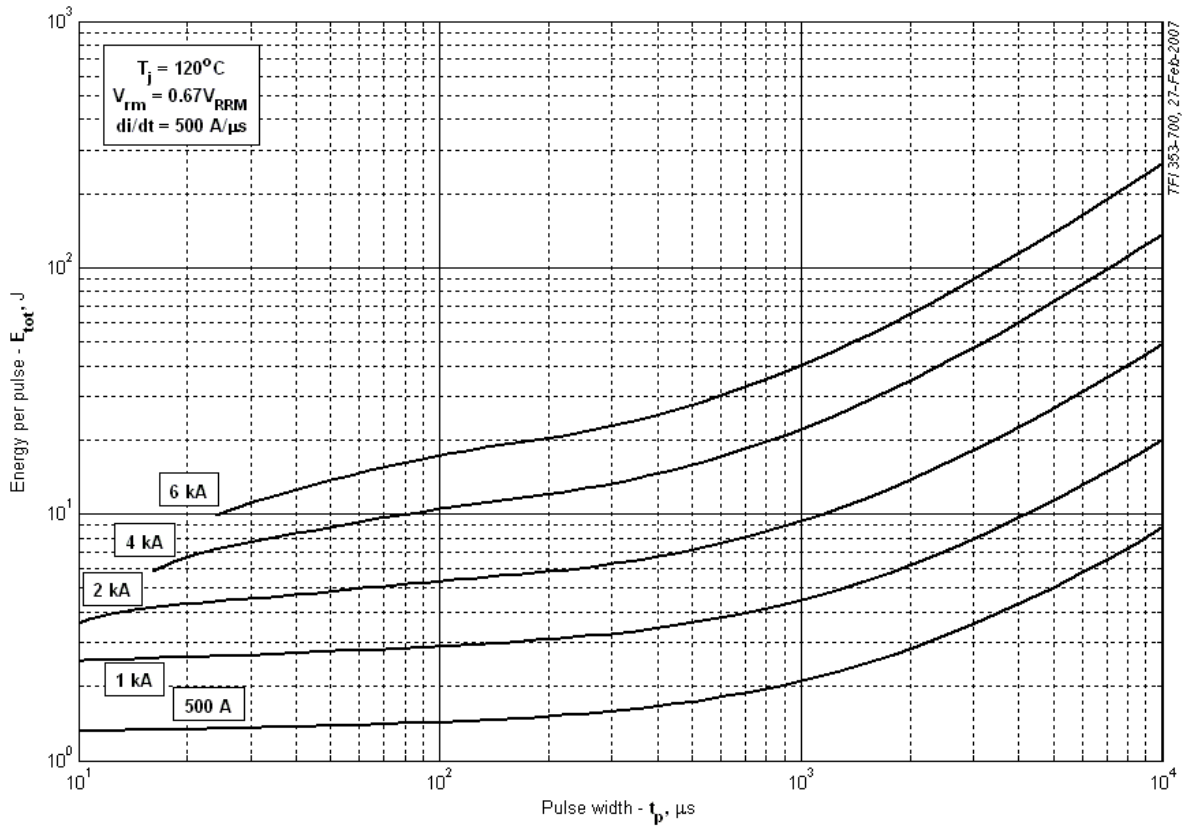


Fig 27 – Square wave energy per pulse

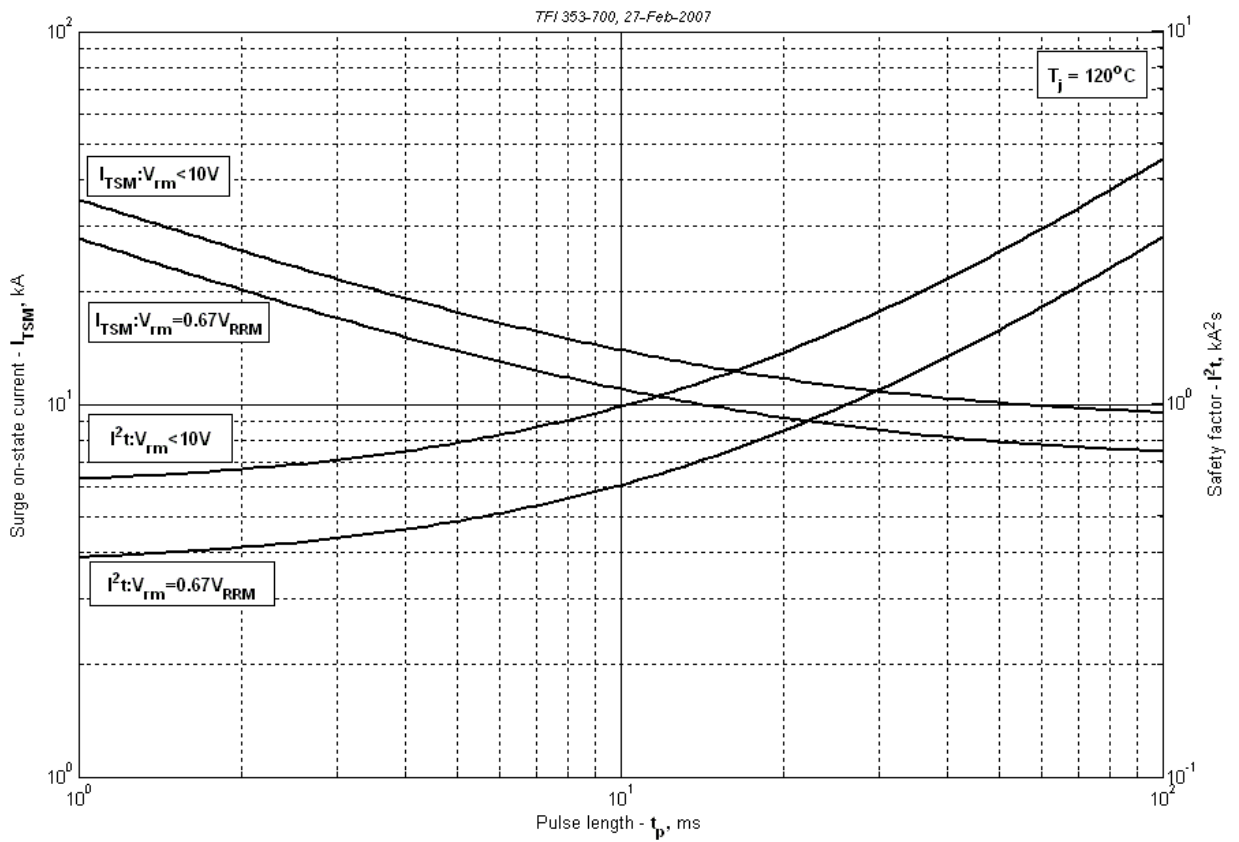


Fig 29 – Maximum surge and I^2t ratings

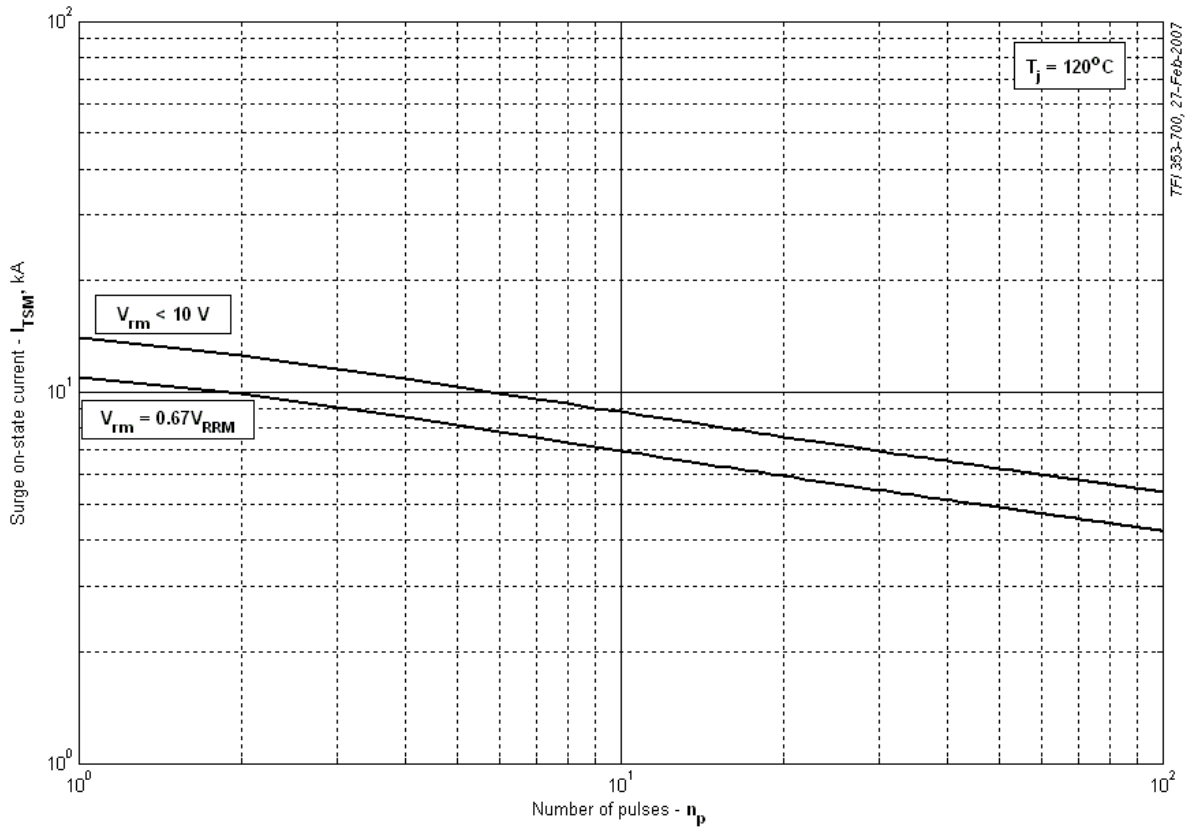


Fig 30 – Maximum surge ratings